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EMC –

Utrustning och metoder för mätning av radiostörningar och immunitet – Del 2-1: Mätning av ledningsbundna störningar

*Specification for radio disturbance and immunity measuring apparatus and methods –
Part 2-1: Methods of measurement of disturbances and immunity –
Conducted disturbance measurements*

Som svensk standard gäller europastandarden EN 55016-2-1:2014. Den svenska standarden innehåller den officiella engelska språkversionen av EN 55016-2-1:2014.

Nationellt förord

Europastandarden EN 55016-2-1:2014

består av:

- **europastandardens ikraftsättningsdokument**, utarbetat inom CENELEC
- **CISPR 16-2-1, Third edition, 2014 - Specification for radio disturbance and immunity measuring apparatus and methods - Part 2-1: Methods of measurement of disturbances and immunity - Conducted disturbance measurements**

utarbetad inom International Electrotechnical Commission, IEC.

Tidigare fastställd svensk standard SS-EN 55016-2-1, utgåva 2, 2009, SS-EN 55016-2-1/A1, utgåva 1, 2011 och SS-EN 55016-2-1/A2, utgåva 1, 2013, gäller ej fr o m 2017-04-02.

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English Version

Specification for radio disturbance and immunity measuring
apparatus and methods - Part 2-1: Methods of measurement of
disturbances and immunity - Conducted disturbance
measurements
(CISPR 16-2-1:2014)

Spécifications des méthodes et des appareils de mesure
des perturbations radioélectriques et de l'immunité aux
perturbations radioélectriques - Partie 2-1: Méthodes de
mesure des perturbations et de l'immunité - Mesures des
perturbations conduites
(CISPR 16-2-1:2014)

Anforderungen an Geräte und Einrichtungen sowie
Festlegung der Verfahren zur Messung der hochfrequenten
Störaussendung (Funkstörungen) und Störfestigkeit - Teil 2-
1: Verfahren zur Messung der hochfrequenten
Störaussendung (Funkstörungen) und Störfestigkeit -
Messung der leitungsgeführten Störaussendung
(CISPR 16-2-1:2014)

This European Standard was approved by CENELEC on 2014-04-02. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

Foreword

The text of document CISPR/A/1053/FDIS, future edition 3 of CISPR 16-2-1, prepared by SC A “Radio-interference measurements and statistical methods” of IEC/TC CISPR “International special committee on radio interference” was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 55016-2-1:2014.

The following dates are fixed:

- latest date by which the document has to be (dop) 2015-01-11
implemented at national level by
publication of an identical national
standard or by endorsement
- latest date by which the national (dow) 2017-04-02
standards conflicting with the
document have to be withdrawn

This document supersedes EN 55016-2-1:2009.

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The text of the International Standard CISPR 16-2-1:2014 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

CISPR 11:2003 + A1:2004	NOTE	Harmonized as EN 55011:2007 ¹⁾ (modified).
CISPR 16-1-4:2010	NOTE	Harmonized as EN 55016-1-4:2010 (not modified).
CISPR 16-2-3:2010	NOTE	Harmonized as EN 55016-2-3:2010 (not modified).
IEC 60364-4 Series	NOTE	Harmonized as HD 60364-4 Series (modified).
IEC 61000-4-6:2008	NOTE	Harmonized as EN 61000-4-6:2009 (modified).
IEC 61010-1:2001	NOTE	Harmonized as EN 61010-1:2001 (modified).

¹⁾ Superseded by EN 55011:2009 (CISPR 11:2009, mod.)

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
CISPR 14-1	-	Electromagnetic compatibility - Requirements for household appliances, electric tools and similar apparatus - Part 1: Emission	EN 55014-1	-
CISPR 16-1-1	2010	Specification for radio disturbance and immunity measuring apparatus and methods - Part 1-1: Radio disturbance and immunity measuring apparatus - Measuring apparatus	EN 55016-1-1	2010
CISPR 16-1-2	2014	Specification for radio disturbance and immunity measuring apparatus and methods - Part 1-2: Radio disturbance and immunity measuring apparatus - Coupling devices for conducted disturbance measurements	EN 55016-1-2	2014
CISPR 16-4-2	-	Specification for radio disturbance and immunity measuring apparatus and methods - Part 4-2: Uncertainties, statistics and limit modelling - Measurement instrumentation uncertainty	EN 55016-4-2	-
IEC 60050	Series	International Electrotechnical Vocabulary	-	-

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INTERNATIONAL ELECTROTECHNICAL COMMISSION
INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE

**SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY
MEASURING APPARATUS AND METHODS –**

**Part 2-1: Methods of measurement of disturbances and immunity –
Conducted disturbance measurements**

FOREWORD

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International Standard CISPR 16-2-1 has been prepared by CISPR subcommittee A: Radio-interference measurements and statistical methods.

This third edition cancels and replaces the second edition published in 2008, Amendment 1:2010 and Amendment 2:2013. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition: Methods of measurement using a new type of ancillary equipment – the CDNE – are added.

The text of this standard is based on the following documents:

FDIS	Report on voting
CISPR/A/1053/FDIS	CISPR/A/1062/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of CISPR 16 series under the general title *Specification for radio disturbance and immunity measuring apparatus and methods*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –

Part 2-1: Methods of measurement of disturbances and immunity – Conducted disturbance measurements

1 Scope

This part of CISPR 16 is designated a basic standard, which specifies the methods of measurement of disturbance phenomena in general in the frequency range 9 kHz to 18 GHz and especially of conducted disturbance phenomena in the frequency range 9 kHz to 30 MHz. With a CDNE, the frequency range is 9 kHz to 300 Hz.

NOTE In accordance with IEC Guide 107, CISPR 16 is a basic EMC standard for use by product committees of the IEC. As stated in Guide 107, product committees are responsible for determining the applicability of the EMC standard. CISPR and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular EMC tests for specific products.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

CISPR 14-1, *Electromagnetic compatibility – Requirements for household appliances, electric tools and similar apparatus – Part 1: Emission*

CISPR 16-1-1:2010, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-1: Radio disturbance and immunity measuring apparatus – Measuring apparatus*

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